

- Member of the Texas Instruments Widebus+™ Family
- Output Edge-Control Circuitry Minimizes Switching Noise in an Unterminated DIMM Load
- Supports SSTL_2 Data Inputs
- Differential Clock (CLK and $\overline{\text{CLK}}$) Inputs
- Supports LVCMOS Switching Levels on the $\overline{\text{RESET}}$ Input
- $\overline{\text{RESET}}$ Input Disables Differential Input Receivers, Resets All Registers, and Forces All Outputs Low
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)

description

This 26-bit registered buffer is designed for 2.3-V to 2.7-V V_{CC} operation.

All inputs are SSTL_2, except the LVCMOS reset ($\overline{\text{RESET}}$) input. All outputs are edge-controlled LVCMOS circuits optimized for unterminated DIMM loads.

The SN74SSTV32867 operates from a differential clock (CLK and $\overline{\text{CLK}}$). Data are registered at the crossing of CLK going high and $\overline{\text{CLK}}$ going low.

The device supports low-power standby operation. When $\overline{\text{RESET}}$ is low, the differential input receivers are disabled, and undriven (floating) data, clock, and reference voltage (V_{REF}) inputs are allowed. In addition, when $\overline{\text{RESET}}$ is low, all registers are reset and all outputs are forced low. The LVCMOS $\overline{\text{RESET}}$ always must be held at a valid logic high or low level.

To ensure defined outputs from the register before a stable clock has been supplied, $\overline{\text{RESET}}$ must be held in the low state during power up.



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SN74SSTV32867

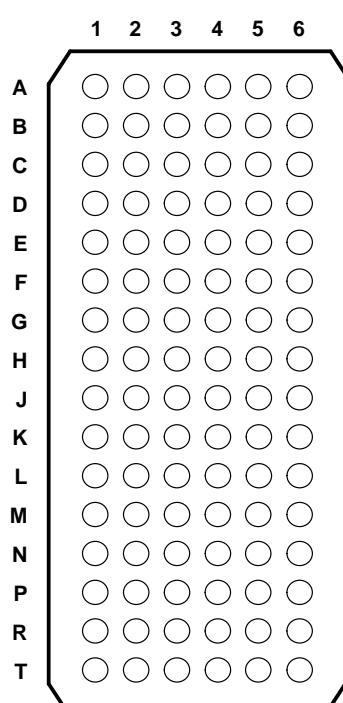
26-BIT REGISTERED BUFFER

WITH SSTL_2 INPUTS AND LVCMS OUTPUTS

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GKE PACKAGE

(TOP VIEW)



terminal assignments

	1	2	3	4	5	6
A	D1	V _{CC}	GND	V _{DDQ}	Q1	Q2
B	D3	D2	V _{REF}	GND	Q3	Q4
C	D5	D4	NC	GND	Q5	Q6
D	D7	D6	GND	V _{DDQ}	Q7	Q8
E	D9	D8	V _{CC}	GND	Q9	V _{DDQ}
F	D11	D10	GND	V _{DDQ}	Q10	GND
G	D13	D12	V _{CC}	V _{DDQ}	Q12	Q11
H	D15	D14	GND	GND	GND	Q13
J	CLK	NC	GND	GND	GND	Q14
K	<u>CLK</u>	<u>RESET</u>	V _{CC}	V _{DDQ}	Q15	Q16
L	D16	D17	GND	V _{DDQ}	Q17	GND
M	D18	D19	V _{CC}	GND	Q18	V _{DDQ}
N	D20	D21	GND	V _{DDQ}	Q20	Q19
P	D22	D23	NC	GND	Q22	Q21
R	D24	D25	NC	GND	Q24	Q23
T	D26	V _{CC}	GND	V _{DDQ}	Q26	Q25

ORDERING INFORMATION

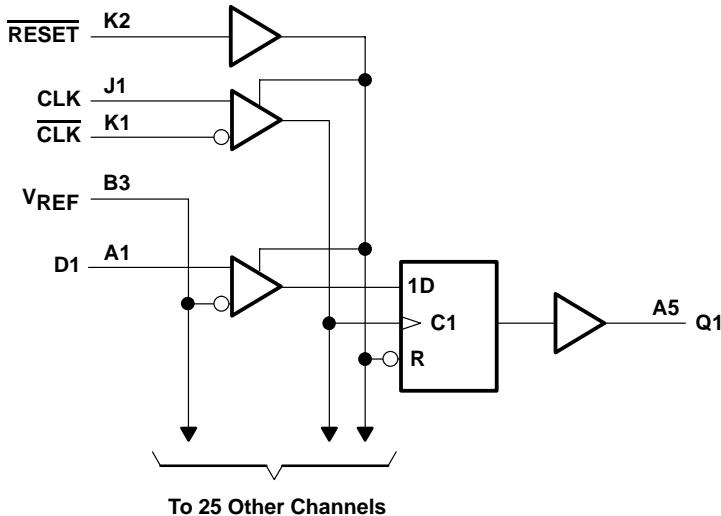
T _A	PACKAGE [†]	ORDERABLE PART NUMBER	TOP-SIDE MARKING
0°C to 70°C	LFBGA – GKE	Tape and reel	SN74SSTV32867GKER

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

INPUTS				OUTPUT Q
RESET	CLK	<u>CLK</u>	D	
H	↑	↓	H	H
H	↑	↓	L	L
H	L or H	L or H	X	Q ₀
L	X or floating	X or floating	X or floating	L

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	–0.5 V to 3.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{DDQ}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} , or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3)	40°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 3.6 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51-7.

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recommended operating conditions (see Note 4)

		MIN	NOM	MAX	UNIT	
V _{CC}	Supply voltage	V _{DDQ}		2.7	V	
V _{DDQ}	Output supply voltage		2.3	2.7	V	
V _{REF}	Reference voltage (V _{REF} = V _{DDQ} /2)		1.15	1.25	1.35	V
V _{TT}	Termination voltage	V _{REF} -40mV	V _{REF}	V _{REF} +40mV	V	
V _I	Input voltage	0	V _{CC}		V	
V _{IH}	AC high-level input voltage	Data input	V _{REF} +310mV		V	
V _{IL}	AC low-level input voltage	Data input		V _{REF} -310mV	V	
V _{IH}	DC high-level input voltage	Data input	V _{REF} +150mV		V	
V _{IL}	DC low-level input voltage	Data input		V _{REF} -150mV	V	
V _{IH}	High-level input voltage	RESET	1.7		V	
V _{IL}	Low-level input voltage	RESET		0.7	V	
V _{ICR}	Common-mode input voltage range	CLK, <u>CLK</u>	0.97	1.53	V	
V _{I(PP)}	Peak-to-peak input voltage	CLK, <u>CLK</u>	360		mV	
I _{OH}	High-level output current			-8	mA	
I _{OL}	Low-level output current			8	mA	
T _A	Operating free-air temperature	0	70		°C	

NOTE 4: The RESET input of the device must be held at V_{CC} or GND to ensure proper device operation. The differential inputs must not be floating unless RESET is low. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC}	MIN	TYP†	MAX	UNIT		
V _{IK}		I _I = -18 mA		2.3 V			-1.2	V		
V _{OH}		I _{OH} = -100 μ A		2.3 V to 2.7 V	V _{DDQ} -0.2			V		
		I _{OH} = -8 mA		2.3 V	1.7					
V _{OL}		I _{OL} = 100 μ A		2.3 V to 2.7 V			0.2	V		
		I _{OL} = 8 mA		2.3 V			0.4			
I _I	All inputs	V _I = V _{CC} or GND		2.7 V			\pm 5	μ A		
I _{CC}	Static standby	RESET = GND	I _O = 0	2.7 V			40	μ A		
	Static operating	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC)					95	mA		
I _{CCD}	Dynamic operating – clock only	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC), CLK and $\overline{\text{CLK}}$ switching 50% duty cycle	I _O = 0	2.5 V			44	μ A/MHz		
	Dynamic operating – per each data input	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC), CLK and $\overline{\text{CLK}}$ switching 50% duty cycle, One data input switching at one-half clock frequency, 50% duty cycle					5	μ A/clock MHz/D input		
C _I ‡	Data inputs	V _I = V _{REF} \pm 310 mV		2.5 V	2.5	3.5	4.5	pF		
	CLK, $\overline{\text{CLK}}$	V _{ICR} = 1.25 V, V _I (PP) = 360mV			4	4.5	5			
	RESET	V _I = V _{CC} or GND			3.9	5	5.5			

† All typical values are at V_{CC} = 2.5 V, T_A = 25°C.

‡ Measured with 50-MHz input frequency

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

				V _{CC} = 2.5 V \pm 0.2 V	UNIT
				MIN	MAX
f _{clock}	Clock frequency			200	MHz
t _w	Pulse duration		CLK, $\overline{\text{CLK}}$ high or low	2.5	ns
t _{act}	Differential inputs active time (see Note 5)			22	ns
t _{inact}	Differential inputs inactive time (see Note 6)			22	ns
t _{su}	Setup time	Fast slew rate (see Notes 7 and 9)	Data before CLK↑, $\overline{\text{CLK}}$ ↓	0.75	ns
		Slow slew rate (see Notes 8 and 9)		0.9	
t _h	Hold time	Fast slew rate (see Notes 7 and 9)	Data after CLK↑, $\overline{\text{CLK}}$ ↓	0.75	ns
		Slow slew rate (see Notes 8 and 9)		0.9	

NOTES: 5. Data inputs must be low a minimum time of t_{act} min, after RESET is taken high.
 6. Data and clock inputs must be held at valid levels (not floating) a minimum time of t_{inact} min, after RESET is taken low.
 7. Data signal input slew rate \geq 1 V/ns
 8. Data signal input slew rate \geq 0.5 V/ns and $<$ 1 V/ns
 9. CLK, $\overline{\text{CLK}}$ input slew rates are \geq 1 V/ns.

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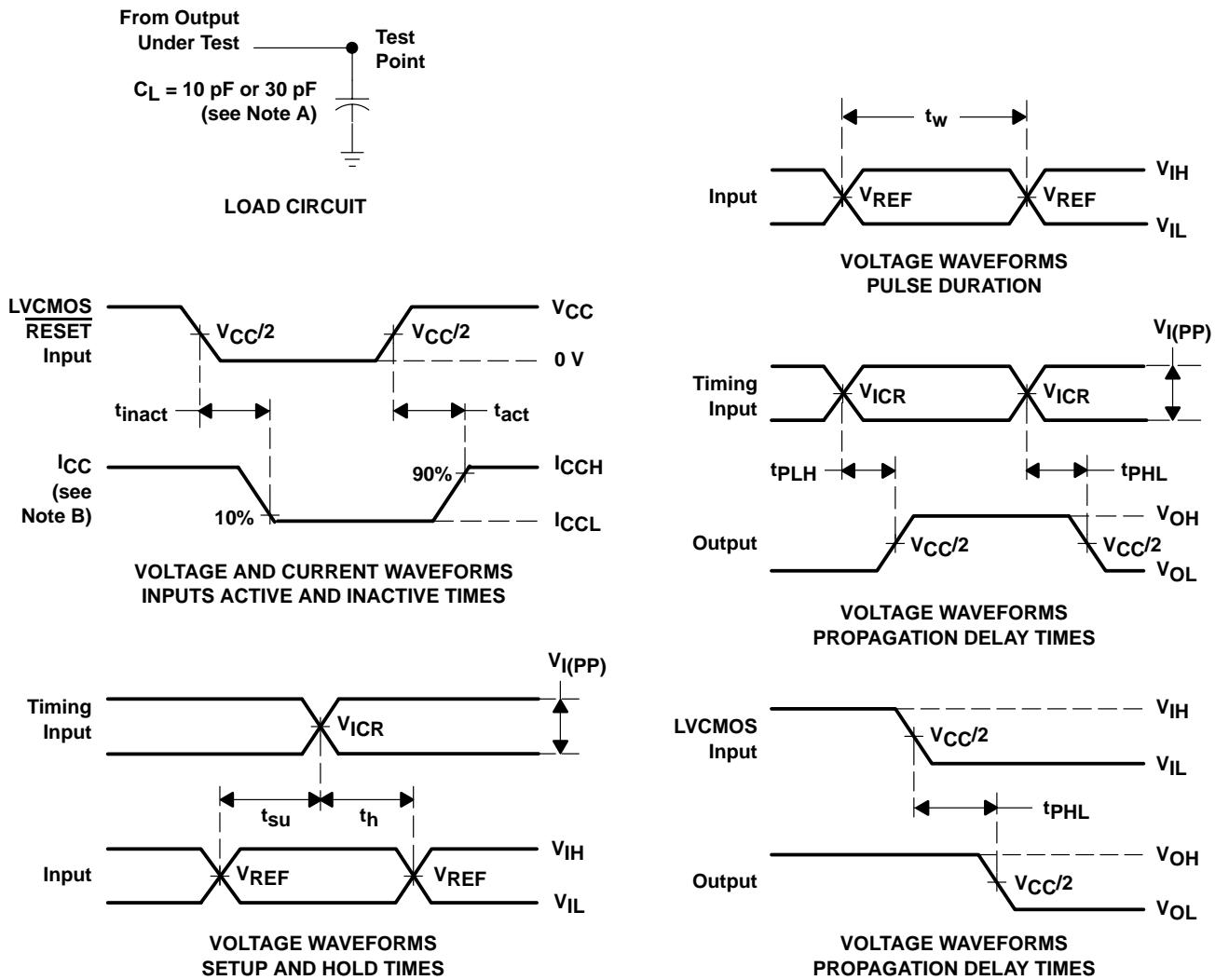
**switching characteristics over recommended operating free-air temperature range,
 $V_{REF} = V_{DDQ}/2$ and $C_L = 10 \text{ pF}$ (unless otherwise noted) (see Figure 1)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$		UNIT
			MIN	MAX	
f_{max}			200		MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Q	1.1	2.8	ns
t_{PHL}	$\overline{\text{RESET}}$	Q	5		ns

**switching characteristics over recommended operating free-air temperature range,
 $V_{REF} = V_{DDQ}/2$ and $C_L = 30 \text{ pF}$ (unless otherwise noted) (see Figure 1)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$		UNIT
			MIN	MAX	
f_{max}			200		MHz
t_{pd}	CLK and $\overline{\text{CLK}}$	Q	1.1	3.8	ns
t_{PHL}	$\overline{\text{RESET}}$	Q	5		ns

PARAMETER MEASUREMENT INFORMATION

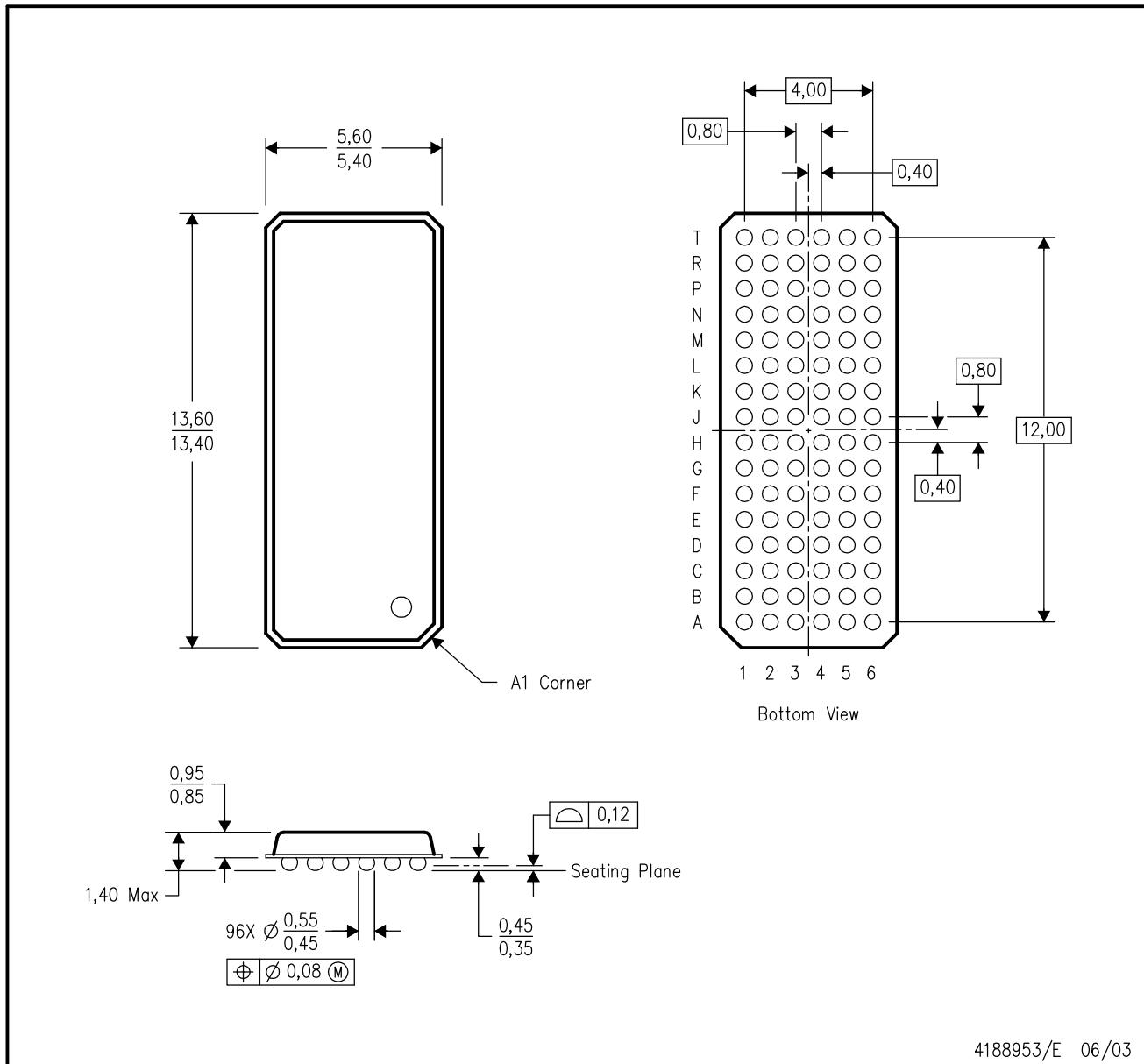


NOTES: A. C_L includes probe and jig capacitance.
 B. I_{CC} tested with clock and data inputs held at V_{CC} or GND, and $I_O = 0$ mA.
 C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, input slew rate = 1 V/ns $\pm 20\%$ (unless otherwise noted).
 D. The outputs are measured one at a time with one transition per measurement.
 E. $V_{REF} = V_{DDQ}/2$
 F. $V_{IH} = V_{REF} + 310$ mV (ac voltage levels) for differential inputs. $V_{IH} = V_{CC}$ for LVC MOS input.
 G. $V_{IL} = V_{REF} - 310$ mV (ac voltage levels) for differential inputs. $V_{IL} = GND$ for LVC MOS input.
 H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

GKE (R-PBGA-N96)

PLASTIC BALL GRID ARRAY



NOTES:

- All linear dimensions are in millimeters.
- This drawing is subject to change without notice.
- MicroStar BGA™ configuration
- Falls within JEDEC MO-205 variation CC.
- This package is tin-lead (SnPb). Refer to the 96 ZKE package (drawing 4204493) for lead-free.

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